

1st CREaTION Workshop
18th November 2013

Synchronous Frequency-Domain Measurements for the Extraction of X-parameters in Digital to Analog Transmitters

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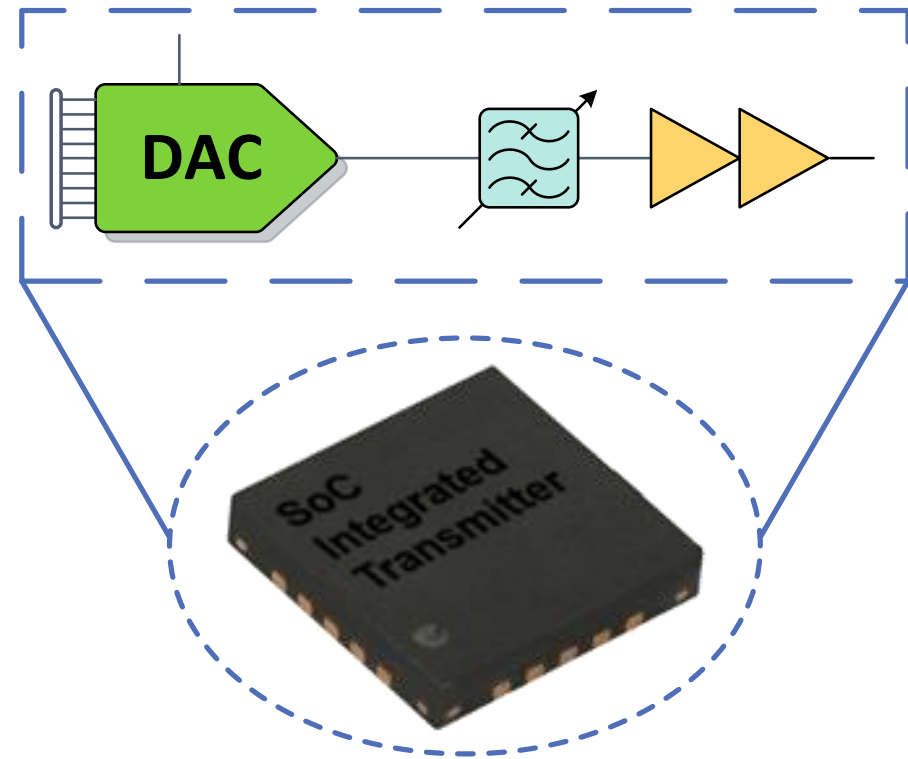
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Introduction & Motivation

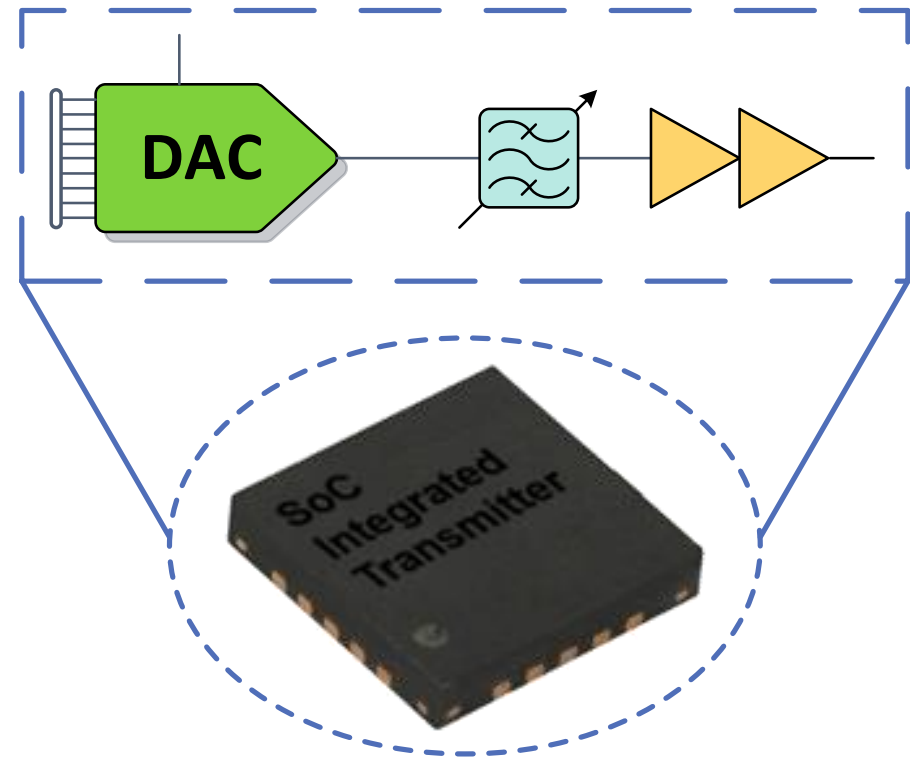
- The radio industry direction for the future is integration
- Integrated **digital to analog transmitters** are one of the most promising technologies
- Though, such components will pose “similar” problems (e.g., nonlinear distortion) as analog-based transmitters



D/A Integrated Transmitter

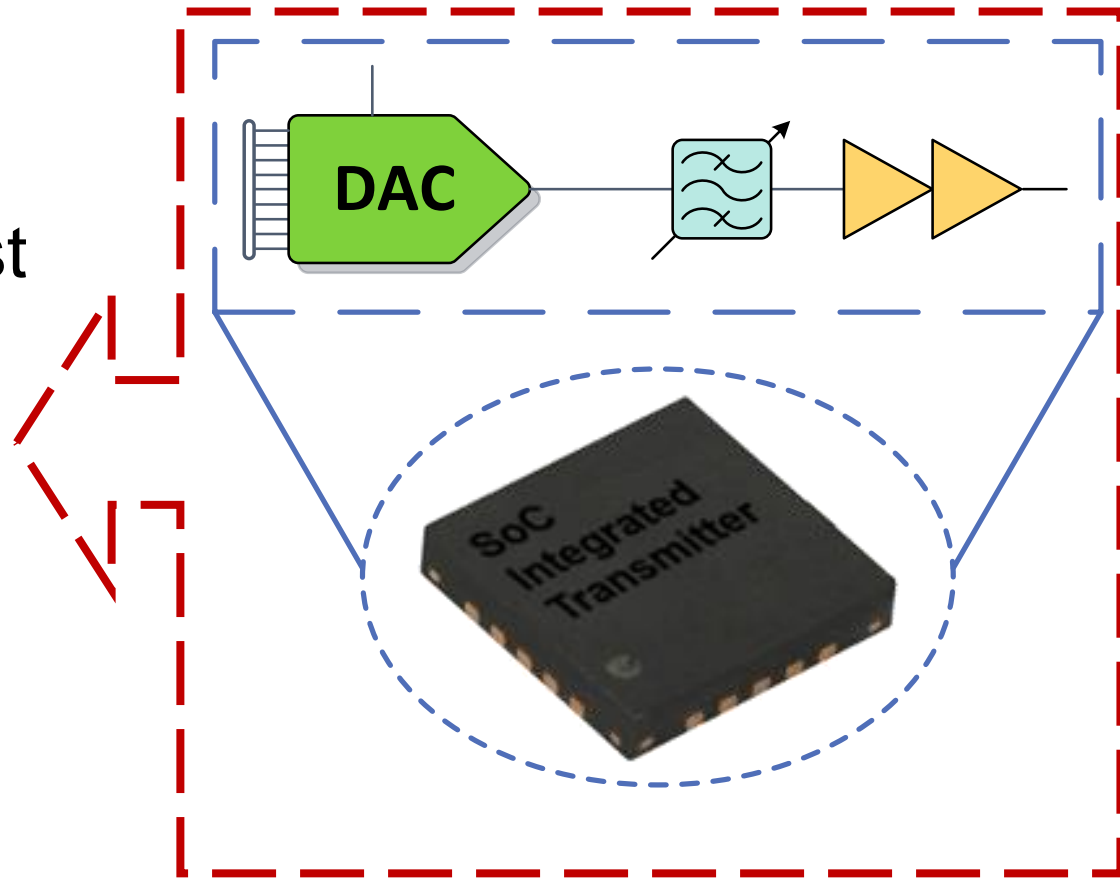
Introduction & Motivation

- It is mandatory to develop models capable of describe the **linear and nonlinear behavior of mixed-signal** (analog/digital) systems or devices
- For **radios integrated in a single IC (SoC)**, it is difficult to measure the only-analog blocks apart from the mixed-signal ones



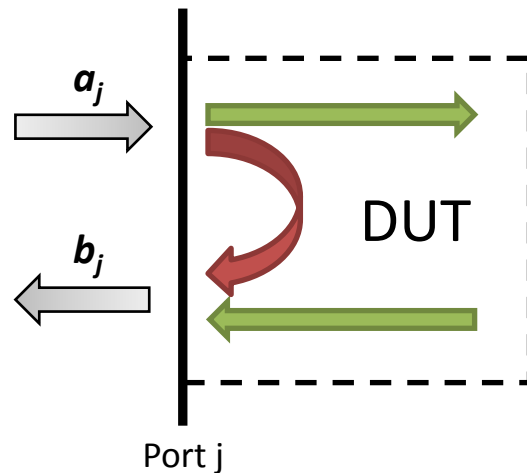
Introduction & Motivation

- Suitable measurement methods and test benches are **essential** to extract meaningful behavioral models



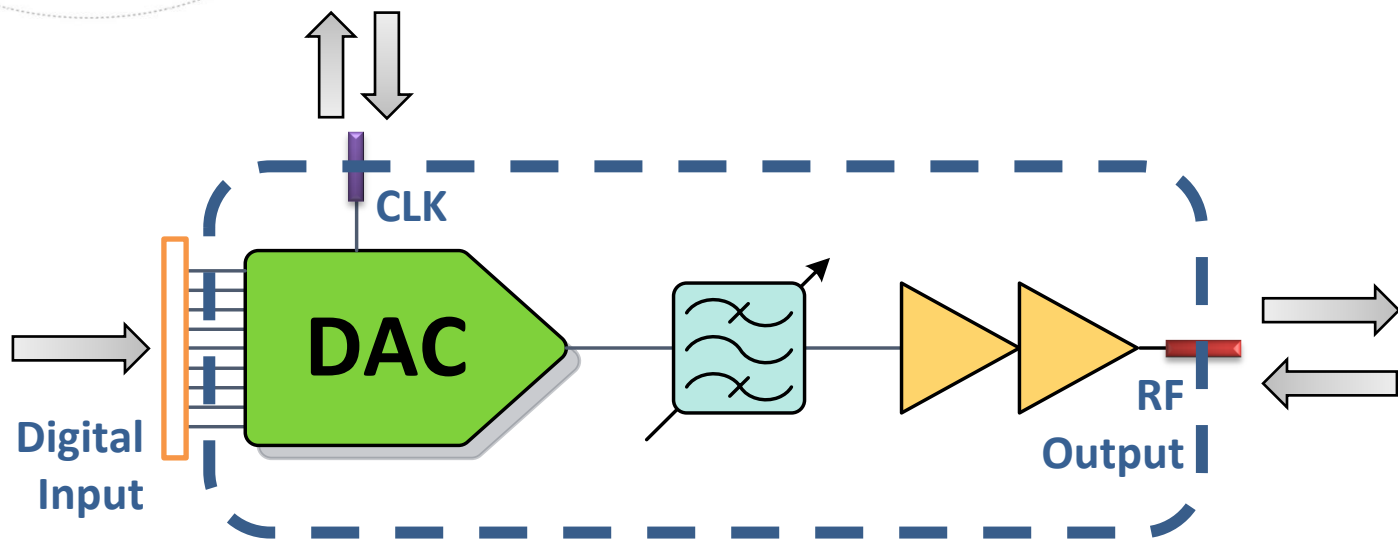
Motivation

- In short... The goal is to:
 - Characterize the entire digital to analog transmitter from an RF point-of-view
 - Use a **scattering waves** framework



Motivation

- In short... The goal is to:
 - Characterize the entire digital-to-analog transmitter from an RF point-of-view
 - Use a **scattering waves** framework



X-Parameters for Mixed-Signal Devices

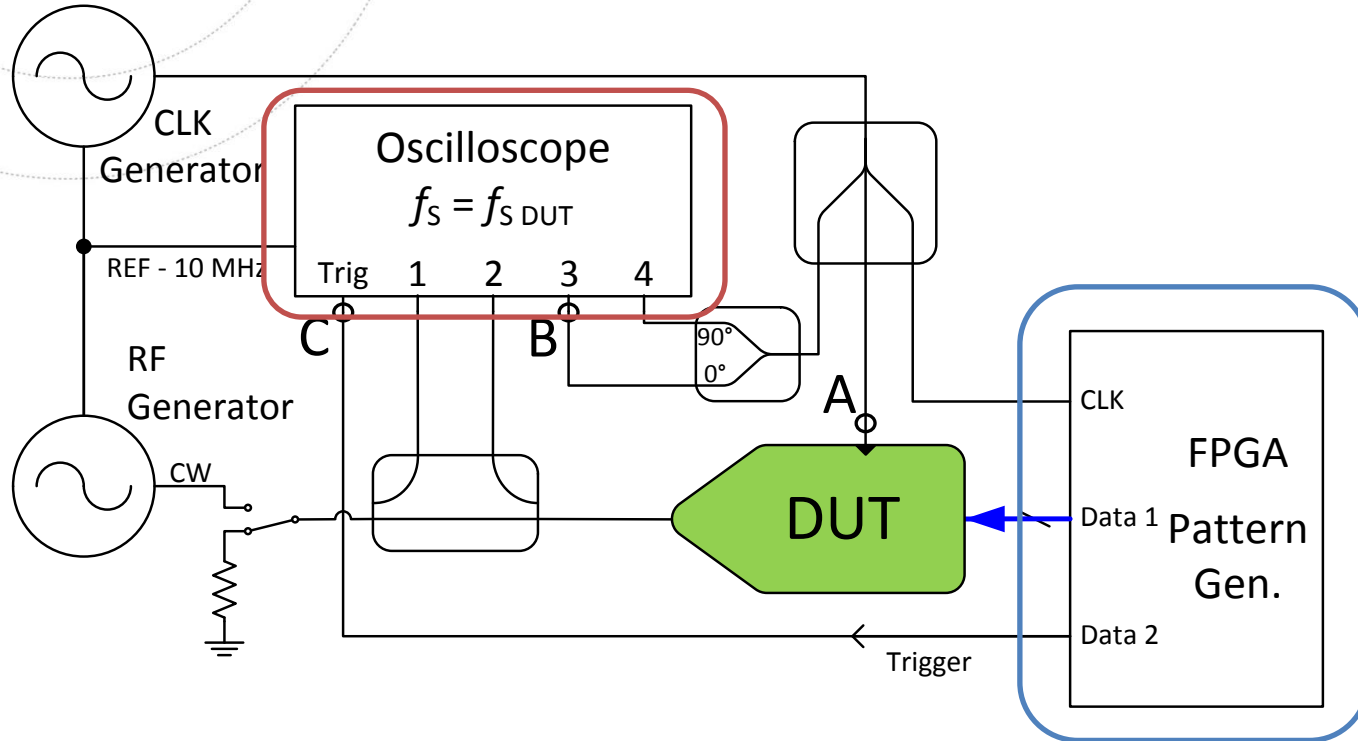
- X-Parameters are a superset of S-Parameters
 - They are based on scattering waves
 - But they require the measurement of absolute waves values for kernel extraction
-
- Instrumentation exists to directly extract the model in fully analog devices
 - But what about **D/A integrated transmitters??**

MEASUREMENT OVERVIEW

- Analog Signal
 - **Sampler-based Receiver (Oscilloscope)**
 - f_S Sampling Receiver = f_S DUT
 - To simplify the synchronization problem
- Digital Signal
 - **FPGA** (Pattern Generator Like)
- Different pieces of hardware for each signal
 - **Synchronization issues will arise**

MEASUREMENT SETUP

- (Oscilloscope)
 - f_S Sampling Receiver = f_S DUT
- (FPGA)

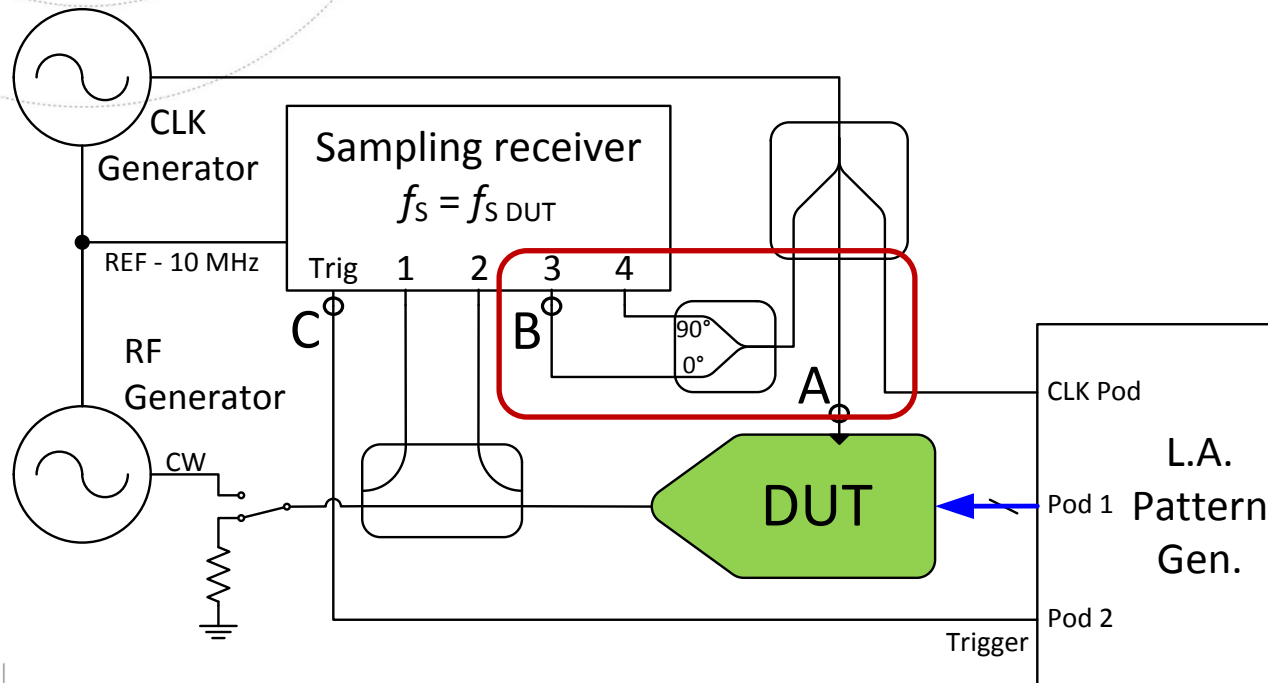


Phase Alignment Procedure

- Since, $f_{S \text{ Sampling Receiver}} = f_{S \text{ DUT}}$
- Only a **phase mismatch** occur between:
 - The sampling instants of the analog signal
 - The sampling instants of the digital signal
- To **synchronize both signals** it is necessary:
 - To know the amount of phase shifting between sampling instants
 - Phase de-trend one of these signals, in this case, the **analog sampled signal**

Phase Alignment Procedure

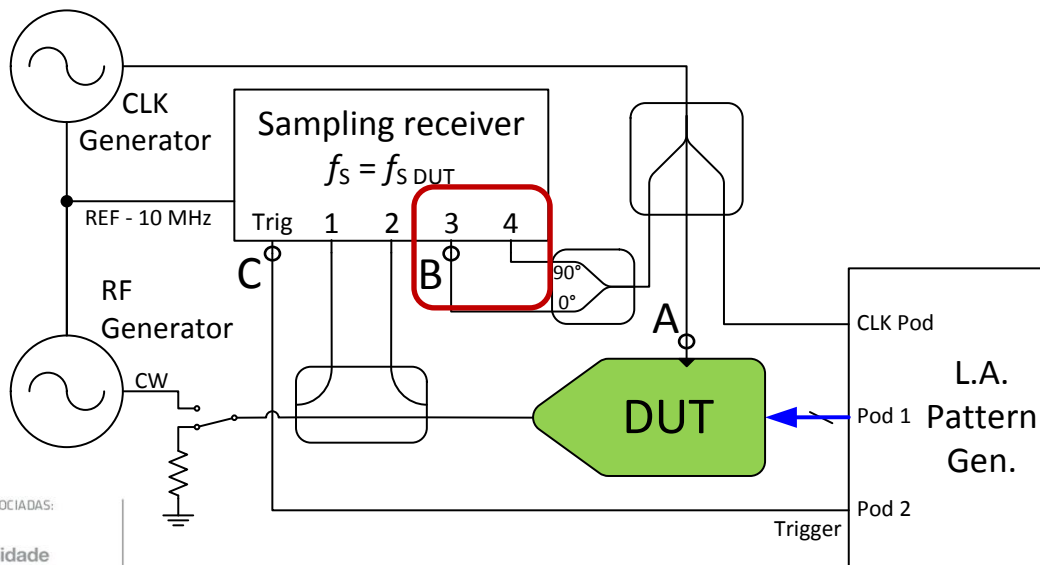
- How to know the amount of phase shift?
- Use a reference signal to track all the sampling instants...
- Reference Signal → DUT Clock Signal (Sinusoidal)



Phase Alignment Procedure

- However, the reference signal received by the analog sampling receiver is a DC voltage, V_3 and V_4
- The following **trigonometric relation** is used to calculate its phase at the receiver sampling instant

$$\tan(\theta'_{analog}) = -\frac{V_4}{V_3} \frac{1}{\cos(\theta_e)} - \tan(\theta_e)$$

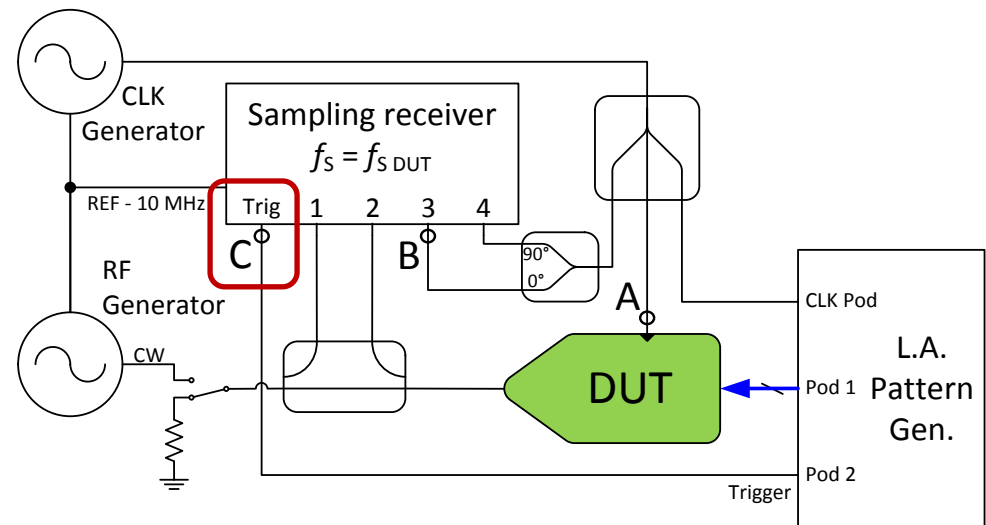


θ'_{analog} - wanted phase

θ_e - hybrid phase error

Phase Alignment Procedure

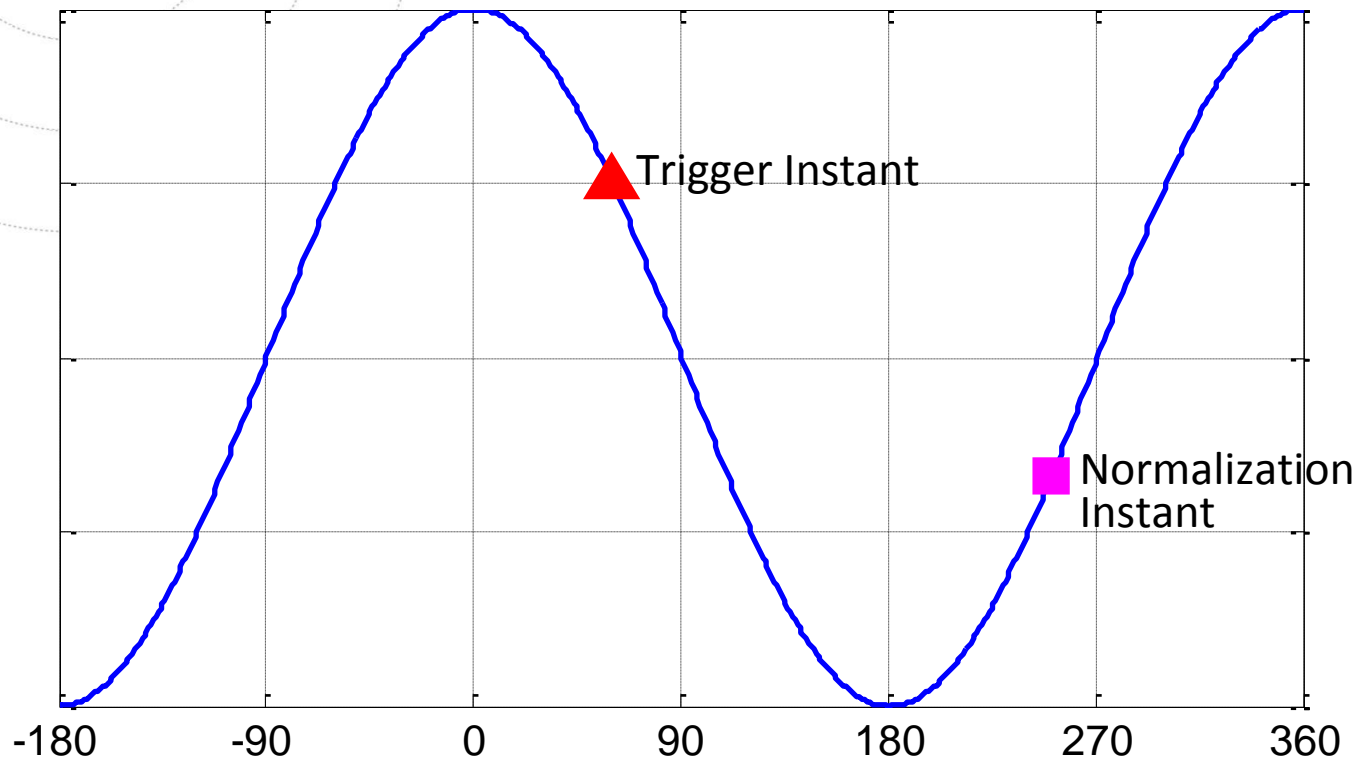
- The **normalization instant** has been chosen to be:
 - -90° of the reference signal (at the **DUT reference plane**)
 - Sampling instant of the DUT
 - An ***a priori*** measurement is needed to know what this normalization instant means at the **analog receiver port plane**
- A **trigger signal** is used to indicate the begin of a measurement
 - Fed into the analog sampling receiver at **point C**



Phase Alignment Procedure - Example

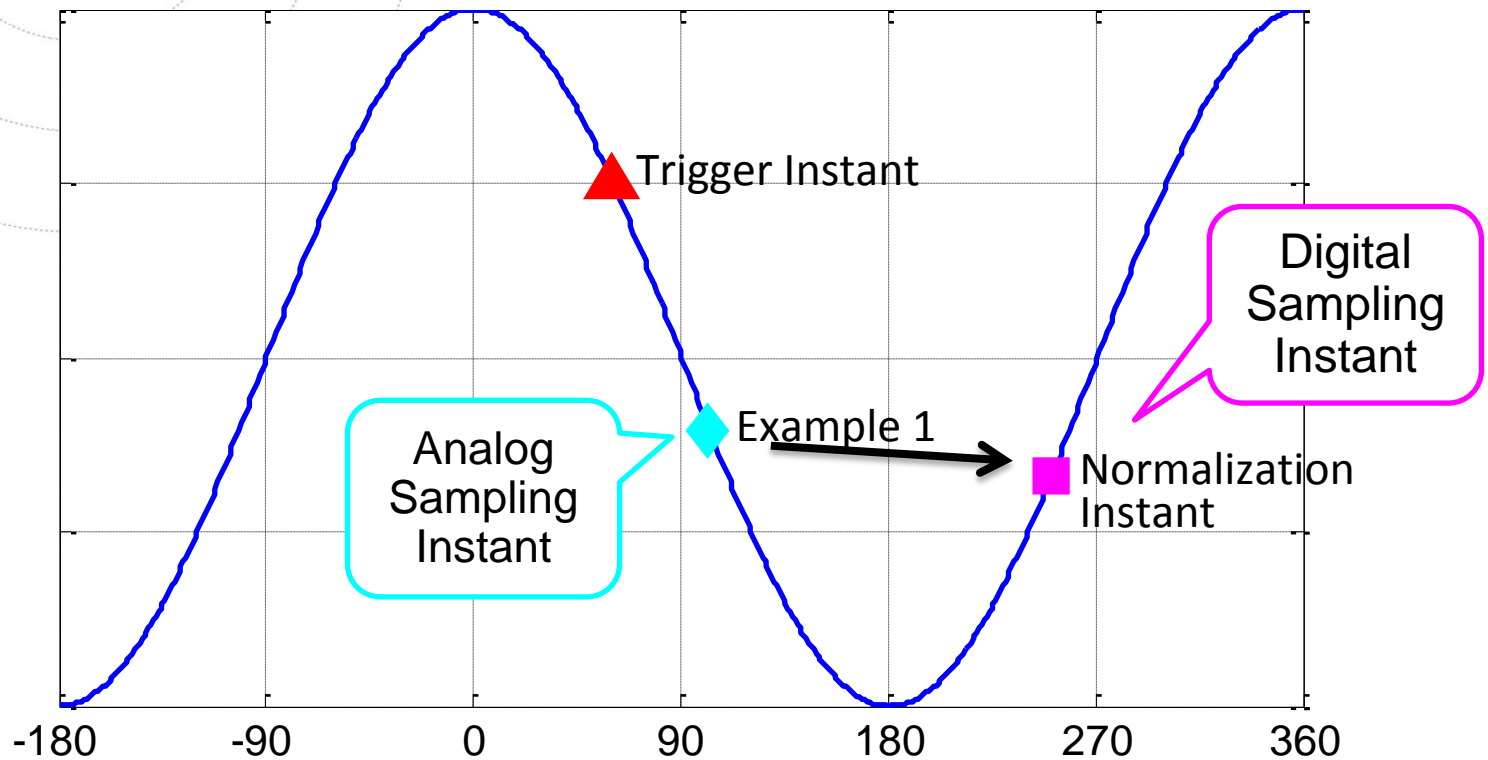
- **Condition to met:**

- The trigger instant must be the **first event to happen**



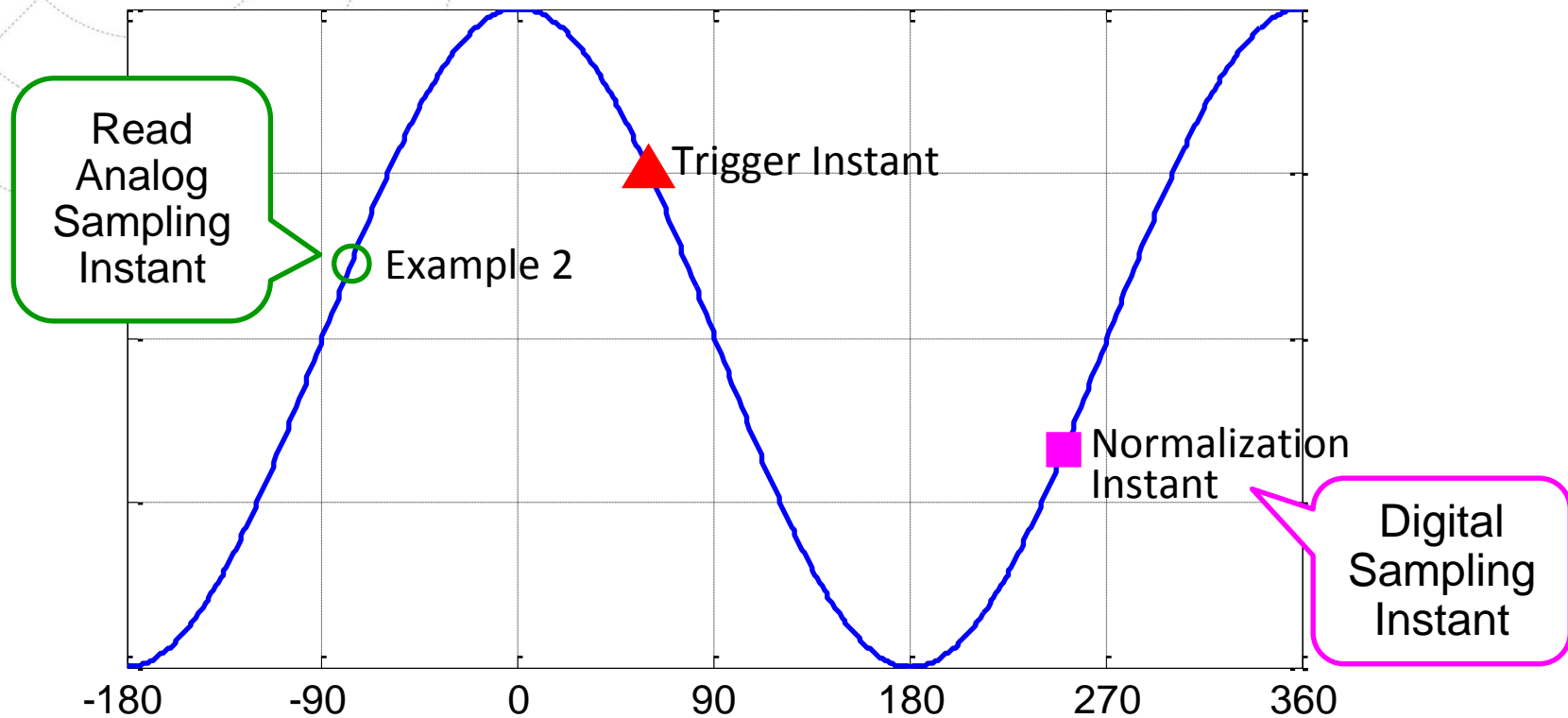
Phase Alignment Procedure - Example 1

- Necessary **phase shift** $\approx +70^\circ$

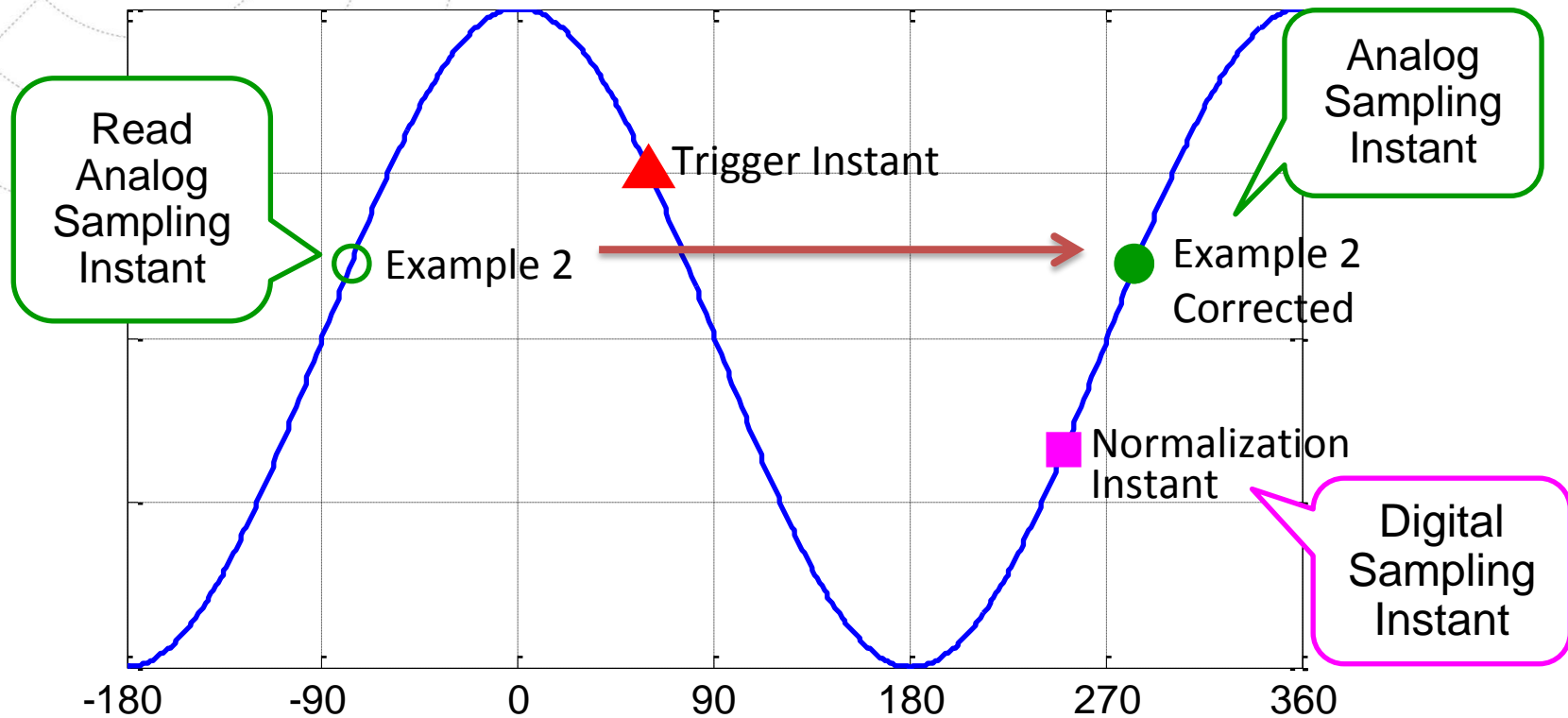


Phase Alignment Procedure - Example 2

- Analog Sampling instant happens before the trigger instant
 - Necessary to correct this ... Add it a **period of 360°**



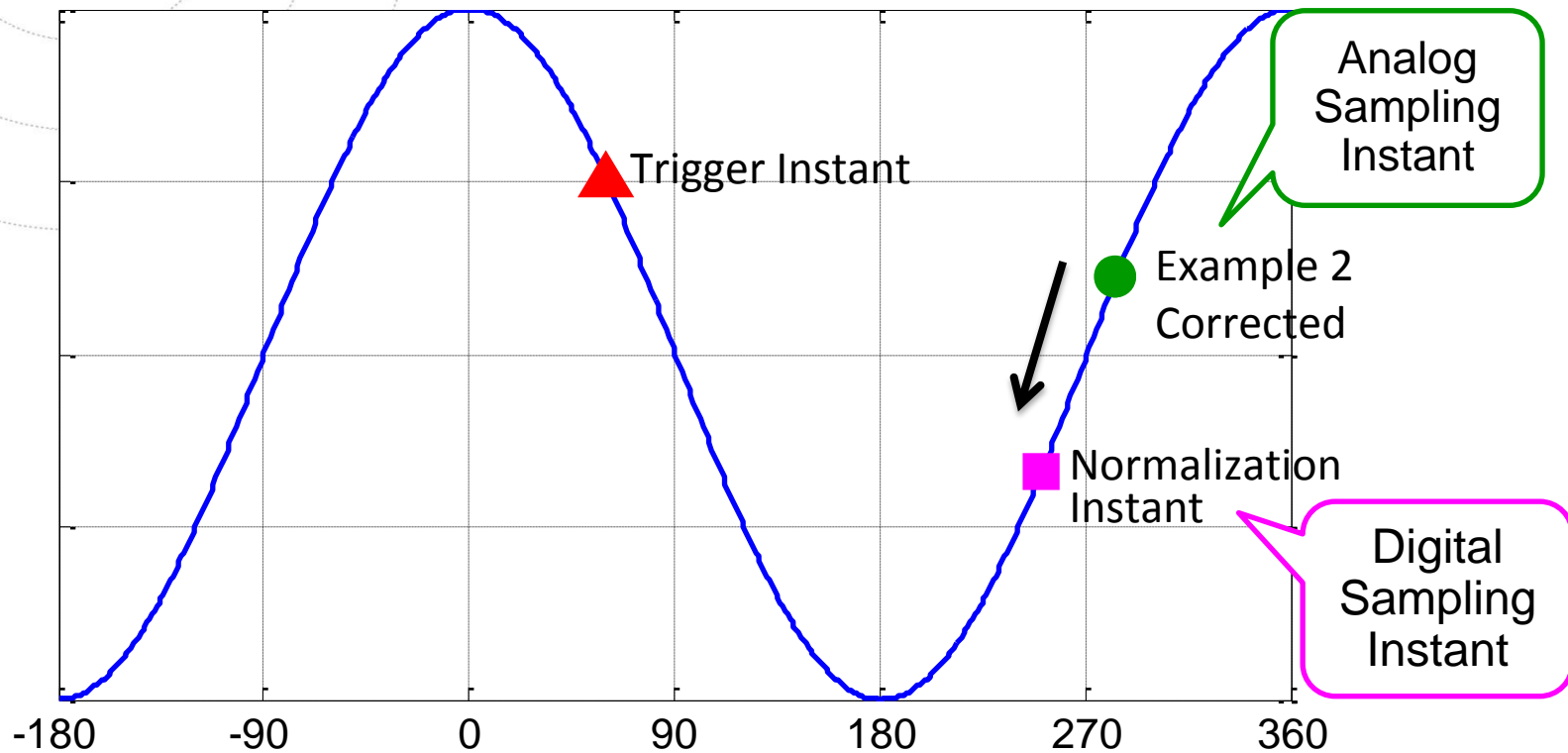
Phase Alignment Procedure - Example 2



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Phase Alignment Procedure - Example 2

- Necessary **phase shift** $\approx -30^\circ$



Phase Alignment Procedure

- Phase calculation is retrieved from the **correct bin** of the time domain signal **FFT transformation**
- To align the analog waves with the digital ones, the expression is used:

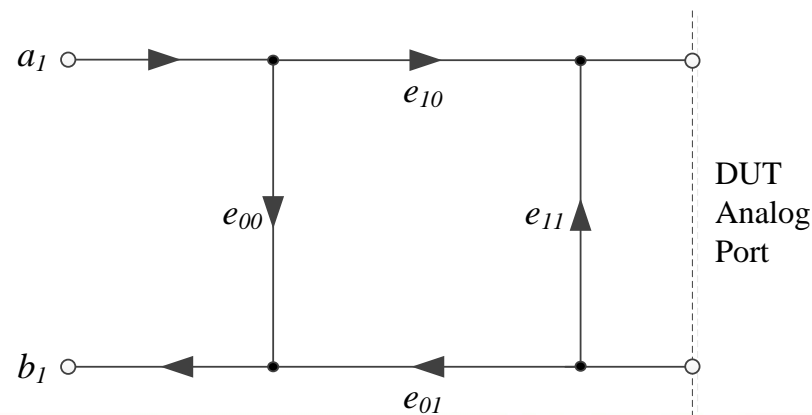
$$C_{k \text{ aligned}} = C_k \cdot e^{(i \Delta\theta f_k / f_s)}$$

- $\Delta\theta = \theta_{norm} - \theta_{analog}$
- $f_s \rightarrow$ sampling frequency
- $C_k \rightarrow$ FFT bin of the signal to be aligned, at index k
- $f_k \rightarrow$ frequency of the previous index k
- $C_{k \text{ aligned}} \rightarrow$ FFT bin of the aligned signal, at index k

Phase Alignment Procedure

Analog Waves Calibration

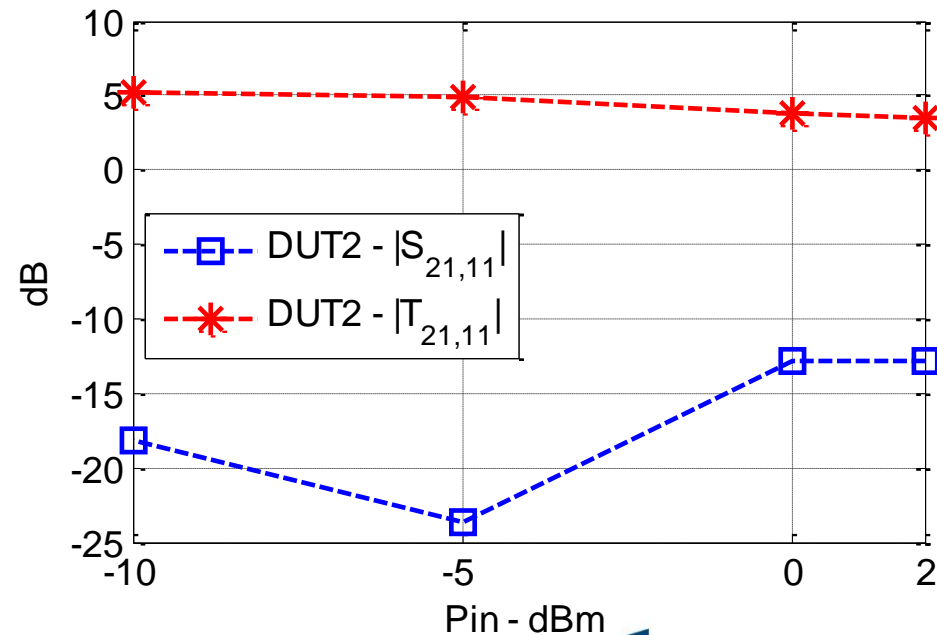
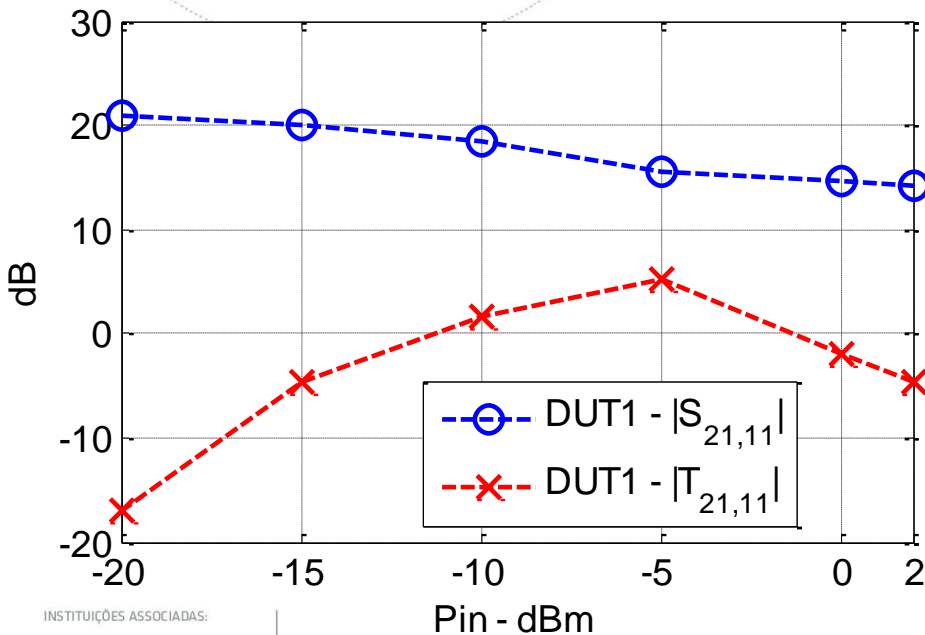
- To correct the measured analog wave quantities
 - A calibration scheme was employed before the **phase alignment procedure**
 - It is based on a 4-term error model
- To individually know the e_{01} and e_{10} error terms an approach similar to the absolute calibration scheme used on NVNAs was used
 - SOL + Absolute Thru



Measurement Results

- **DUT1** → DAC + low-pass filter + PA
- **DUT2** → DAC + band-pass filter + PA

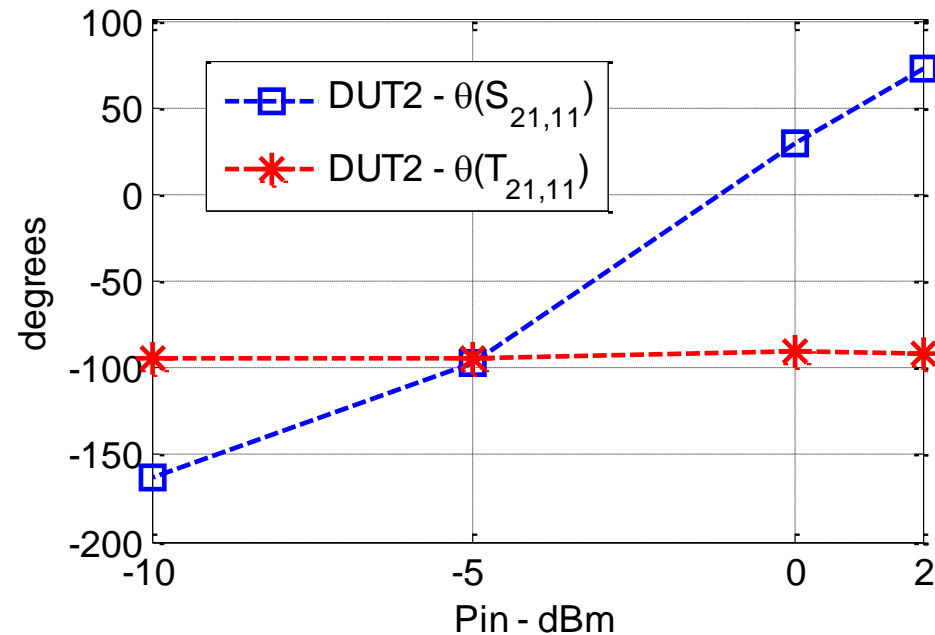
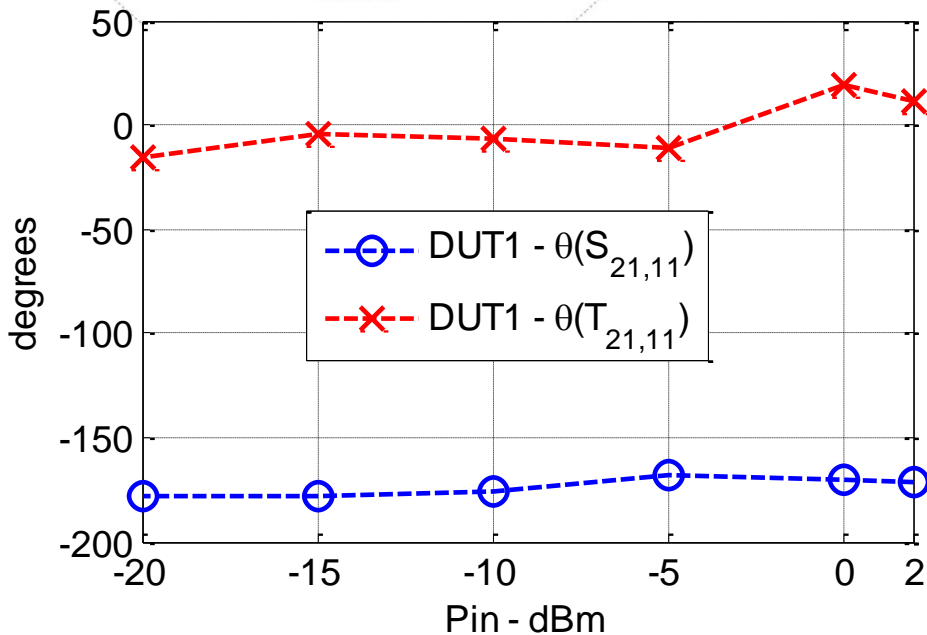
- **DUT1** - $S_{21,11}$ parameter is dominant
 - 1st Nyquist zone → direct phase response
- **DUT2** - $T_{21,11}$ parameter is dominant
 - 2nd Nyquist zone → conjugate phase response



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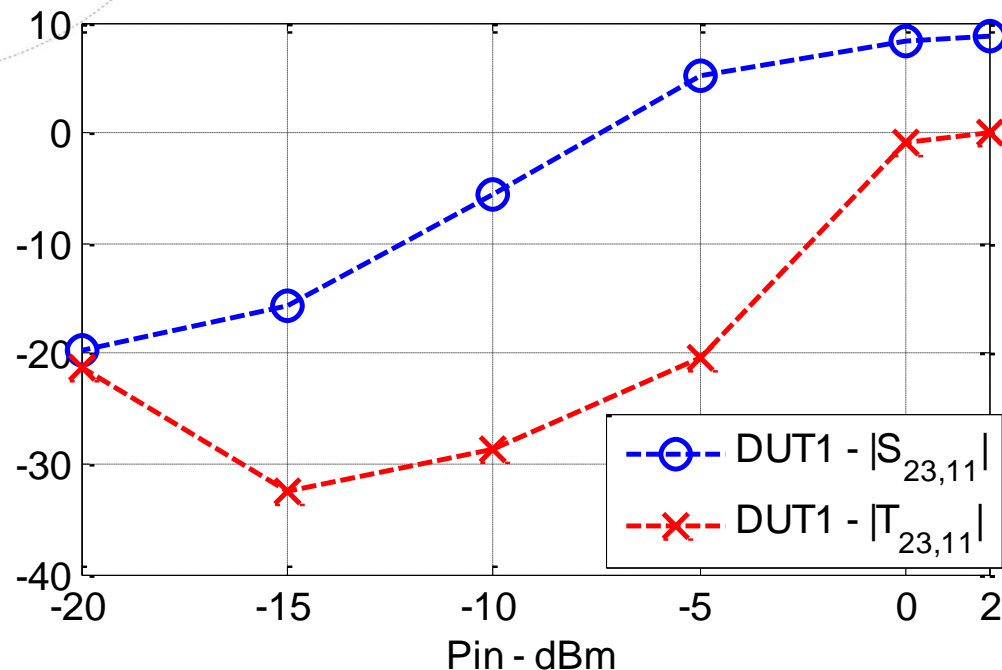
Measurement Results

- Phase values for the same parameters were also extracted
- With a high repeatability from extraction to extraction



Measurement Results - DUT1

- Magnitude and phase behaviors of $S_{23,11}$ and $T_{23,11}$
- The contribution of the **fundamental at the input** to the **third harmonic at the output** increase as expected



Conclusion

- A first approach to the extraction of **X-parameters** of complete **Digital to Analog integrated transmitters** has been presented
- The extraction validity was proved with meaningful measurements of different **D/A transmitter DUT's**
- These measurements mimic the expected behavior of such an integrated transmitter



Thank you!!!



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